

Insulated Gate Bipolar Transistor Protected Logic-Level IGBT

BUK866-400 IZ**GENERAL DESCRIPTION**

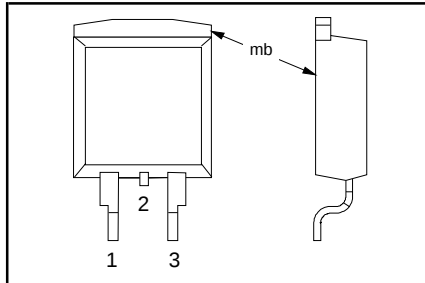
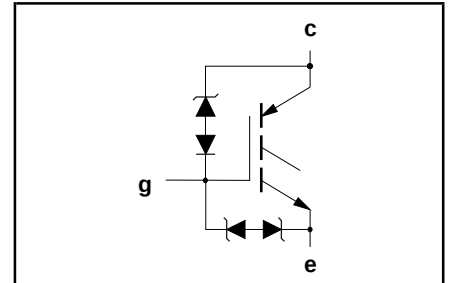
Protected N-channel logic-level insulated gate bipolar power transistor in a plastic envelope suitable for surface mount applications. It is intended for automotive ignition applications, and has integral zener diodes providing active collector voltage clamping and ESD protection up to 2 kV.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
$V_{(CL)CER}$	Collector-emitter clamp voltage	370	410	500	V
V_{CEsat}	Collector-emitter on-state voltage			2.2	V
I_C	Collector current (DC)			20	A
P_{tot}	Total power dissipation			100	W
E_{CERS}	Clamped energy dissipation			300	mJ

PINNING - SOT404

PIN	DESCRIPTION
1	gate
2	collector
3	emitter
tab	collector

PIN CONFIGURATION**SYMBOL****LIMITING VALUES**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{CE}	Collector-emitter voltage	$t_p \leq 500 \mu s$	-	500	V
V_{CE}	Collector-emitter voltage	Continuous	-20	50	V
$\pm V_{GE}$	Gate-emitter voltage	-	-	12	V
I_C	Collector current (DC)	$T_{mb} = 100^\circ C$	-	10	A
I_C	Collector current (DC)	$T_{mb} = 25^\circ C$	-	20	A
I_{CM}	Collector current (pulsed peak value, on-state)	$T_{mb} = 25^\circ C$; $t_p \leq 10 ms$; $V_{CE} \leq 15 V$	-	25	A
I_{CLM}	Collector current (clamped inductive load)	$1 k\Omega \leq R_G \leq 10 k\Omega$	-	10	A
E_{CERS}	Clamped turn-off energy (non-repetitive)	$T_{mb} = 25^\circ C$; $I_C = 10 A$; $R_G = 1 k\Omega$; see Figs. 23,24	-	300	mJ
E_{CERR}	Clamped turn-off energy (repetitive)	$T_{mb} = 125^\circ C$; $I_C = 8 A$; $R_G = 1 k\Omega$; $f = 50 Hz$; $t = 60 min.$	-	125	mJ
E_{ECR}	Reverse avalanche energy (repetitive)	$I_E = 1 A$; $f = 50 Hz$	-	5	mJ
P_{tot}	Total power dissipation	$T_{mb} = 25^\circ C$	-	125	W
T_{stg}	Storage temperature	-	-55	150	$^\circ C$
T_J	Operating Junction Temperature	-	-40	150	$^\circ C$

ESD LIMITING VALUE

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_C	Electrostatic discharge capacitor voltage	Human body model (100 pF, 1.5 k Ω)	-	2	kV

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THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT
$R_{th\ j-mb}$	Thermal resistance junction to mounting base	-	-	1.0	K/W
$R_{th\ j-a}$	Thermal resistance junction to ambient	minimum footprint, FR4 board (see Fig. 26).	50	-	K/W

STATIC CHARACTERISTICS

 $T_{mb} = 25\ ^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)CG}$	Collector-gate zener breakdown voltage	$2\text{ mA} \leq -I_G \leq 5\text{ mA}$; $-40 \leq T_j \leq 150^\circ\text{C}$	370	410	500	V
$V_{(BR)EC}$	Reverse collector-emitter breakdown voltage	$I_E = 10\text{ mA}$	20	30	50	V
$\pm V_{(BR)GES}$	Gate-emitter breakdown voltage	$I_G = \pm 1\text{ mA}$	12	16	20	V
$V_{GE(TO)}$	Gate threshold voltage	$V_{CE} = V_{GE}$; $I_C = 1\text{ mA}$	1	1.5	2	V
$V_{GE(TO)}$	Gate threshold voltage	$V_{CE} = V_{GE}$; $I_C = 1\text{ mA}$; $-40 \leq T_j \leq 150^\circ\text{C}$	0.6	-	2.4	V
I_{CES}	Zero gate voltage collector current	$V_{CE} = 50\text{ V}$; $V_{GE} = 0\text{ V}$; $T_j = 25\ ^\circ\text{C}$	-	0.01	10	μA
I_{CES}	Zero gate voltage collector current	$T_j = 125\ ^\circ\text{C}$	-	0.01	1	mA
I_{EC}	Reverse collector current	$V_{CE} = -20\text{ V}$	-	0.2	5	mA
I_{EC}	Reverse collector current	$V_{CE} = -20\text{ V}$; $T_j = 125^\circ\text{C}$	-	2	20	mA
I_{GES}	Gate emitter leakage current	$V_{GE} = \pm 6\text{ V}$; $T_j = 150^\circ\text{C}$	-	0.1	1	μA
V_{CESat}	Collector-emitter on-state voltage	$V_{GE} = 4.5\text{ V}$; $I_C = 8\text{ A}$; $V_{GE} = 3.5\text{ V}$; $I_C = 6\text{ A}$; $-40 \leq T_j \leq 150^\circ\text{C}$	-	1.2	2.2	V
			-	1.2	2.2	V

DYNAMIC CHARACTERISTICS

 $T_{mb} = 25\ ^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(CL)CER}$	Collector-emitter clamp voltage (peak value)	$R_G = 1\text{ k}\Omega$; $I_C = 10\text{ A}$; $-40 \leq T_j \leq 150^\circ\text{C}$; Inductive load; see Figs. 23,24	370	410	500	V
g_{fe}	Forward transconductance	$V_{CE} = 15\text{ V}$; $I_C = 4\text{ A}$	5.5	15	20	S
C_{ies}	Input capacitance	$V_{GE} = 0\text{ V}$; $V_{CE} = 25\text{ V}$; $f = 1\text{ MHz}$	-	940	1200	pF
C_{oes}	Output capacitance		-	95	130	pF
C_{res}	Feedback capacitance		-	30	50	pF
$t_{d\ off}$	Turn-off delay time	$I_C = 8\text{ A}$; $V_{CL} = 300\text{ V}$; $R_G = 1\text{ k}\Omega$;	-	13	18	μs
t_f	Fall time	$V_{GE} = 5\text{ V}$; $T_j = 125^\circ\text{C}$;	-	6	10	μs
t_c	Crossover Time	Inductive load; see Figs. 20,21	-	12	-	μs
E_{off}	Turn-off Energy loss		-	13	-	mJ

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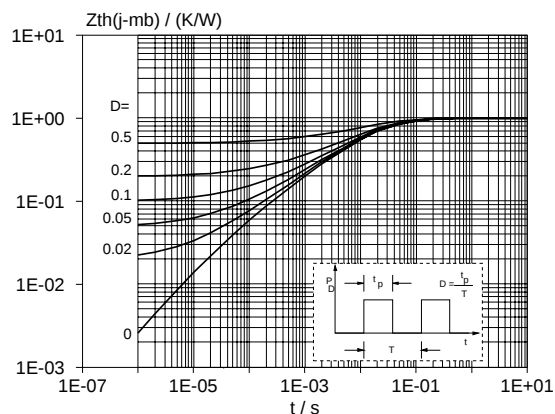


Fig.1. Transient thermal impedance
 $Z_{th(j-mb)} = f(t)$; parameter $D = t_p/T$

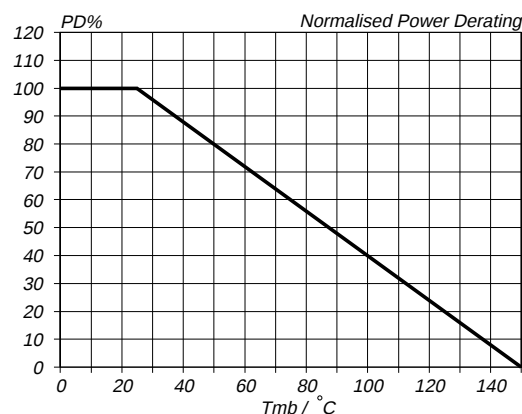


Fig.4. Normalised power dissipation.
 $PD\% = 100 \cdot P_D / P_{D 25^\circ C} = f(T_{mb})$

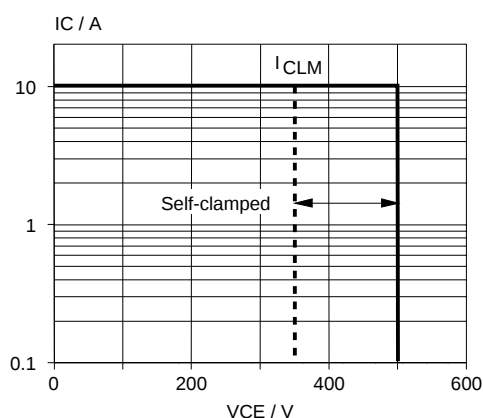


Fig.2. Turn-off Safe Operating Area
conditions: $T_j \leq T_{jmax.}$; $R_G \geq 1 \text{ k}\Omega$

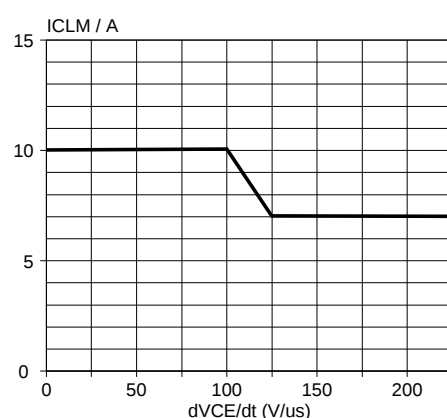


Fig.5. Derating of I_{CLM} with turn-off dV_{CE}/dt
conditions: $V_{CE} \leq 500 \text{ V}$; $T_j \leq T_{jmax.}$

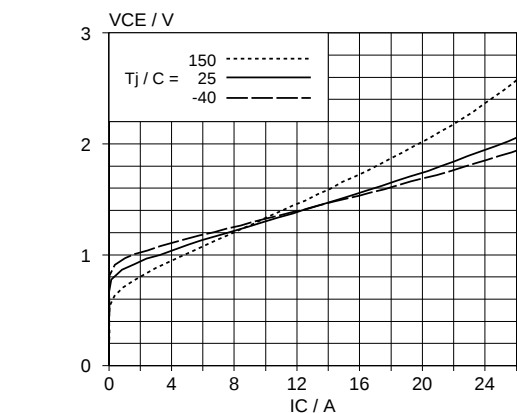


Fig.3. Typical On-state Voltage
 $V_{CEsat} = f(I_C)$; parameter T_j ; conditions: $V_{GE} = 3.5 \text{ V}$

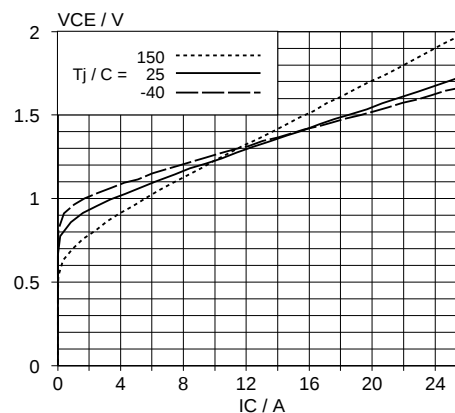


Fig.6. Typical On-state Voltage
 $V_{CEsat} = f(I_C)$; parameter T_j ; conditions: $V_{GE} = 5 \text{ V}$

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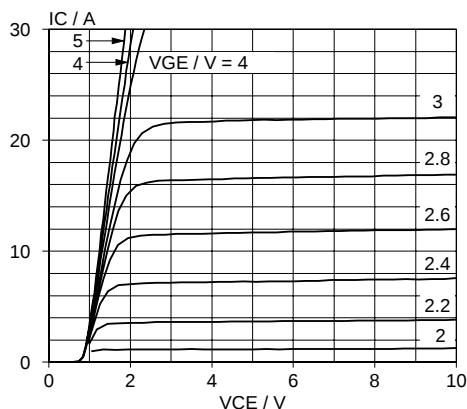


Fig. 7. Typical Output Characteristics
 $I_C = f(V_{CE})$; parameter V_{GE} ; conditions: $T_j = 25^\circ\text{C}$

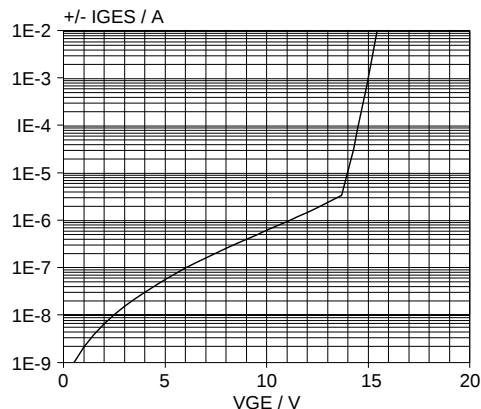


Fig. 10. Typical gate-emitter characteristics
 $I_{GE} = f(V_{GE})$; conditions: $V_{CE} = 0\text{ V}$; $T_j = 25^\circ\text{C}$

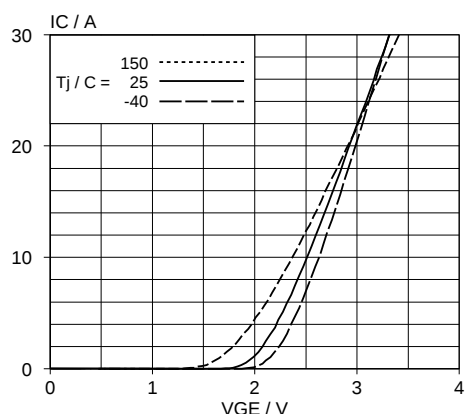


Fig. 8. Typical Transfer Characteristics
 $I_C = f(V_{GE})$, parameter T_j ; conditions: $V_{CE} = 10\text{ V}$

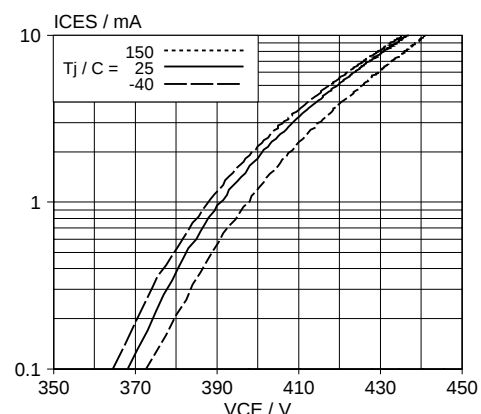


Fig. 11. Typical collector clamp characteristics
 $I_{CES} = f(V_{CE})$; parameter T_j ; conditions: $V_{GE} = 0\text{ V}$

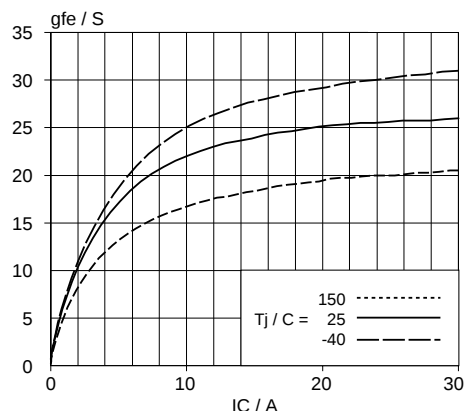


Fig. 9. Typical Forward Transconductance
 $g_{fe} = f(I_C)$; parameter T_j ; conditions: $V_{CE} = 10\text{ V}$

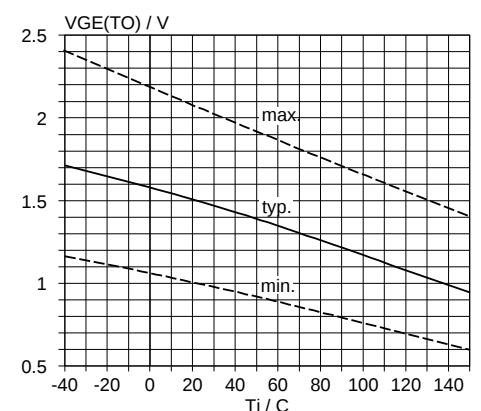


Fig. 12. Gate Threshold Voltage
 $V_{GE(TH)} = f(T_j)$; conditions: $I_C = 1\text{ mA}$; $V_{CE} = V_{GE}$

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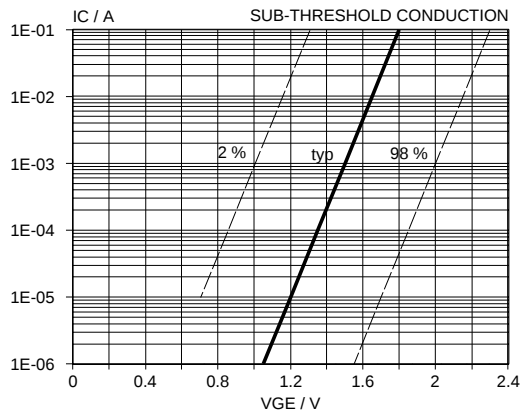


Fig.13. Sub-threshold collector current
 $I_C = f(V_{GE})$; $T_J = 25^\circ\text{C}$; $V_{CE} = V_{GE}$

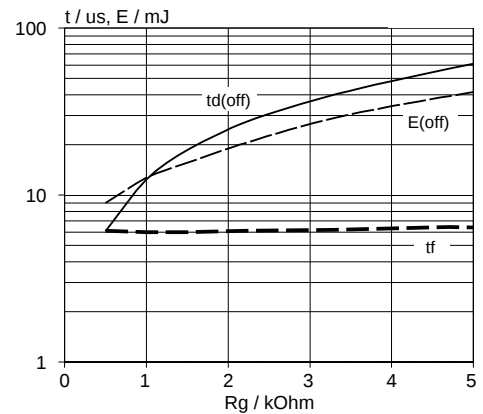


Fig.16. Typical Switching Characteristics vs. R_G
conditions: $T_J = 125^\circ\text{C}$; $I_C = 8\text{ A}$; $V_{CL} = 300\text{ V}$; $L_C = 5\text{ mH}$.

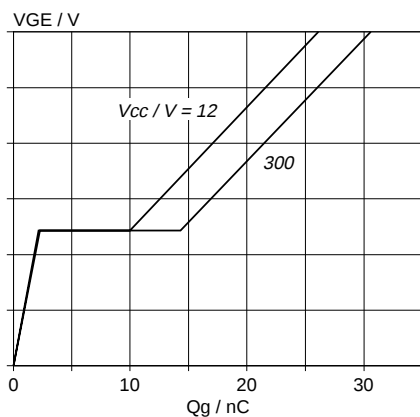


Fig.14. Typical Turn-on Gate Charge Characteristics
 $V_{GE} = f(Q_G)$; conditions: $I_C = 8\text{ A}$.

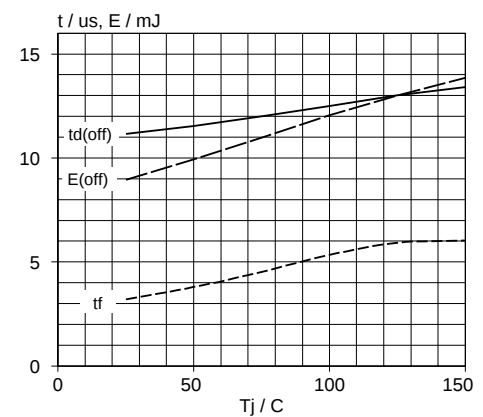


Fig.17. Typical Switching Characteristics vs. T_J
conditions: $I_C = 8\text{ A}$; $V_{CL} = 300\text{ V}$; $R_G = 1\text{ k}\Omega$; $L_C = 5\text{ mH}$.

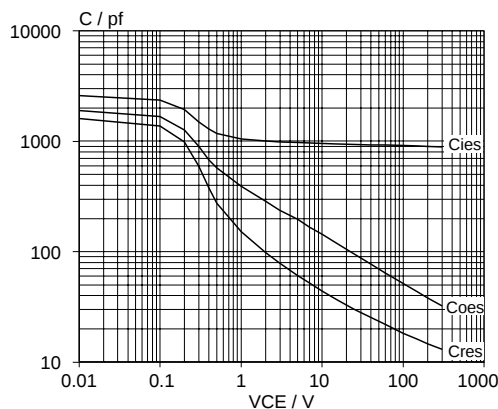


Fig.15. Typical Capacitances C_{ies} , C_{oes} , C_{res}
 $C = f(V_{CE})$; conditions: $V_{GE} = 0\text{ V}$; $f = 1\text{ MHz}$

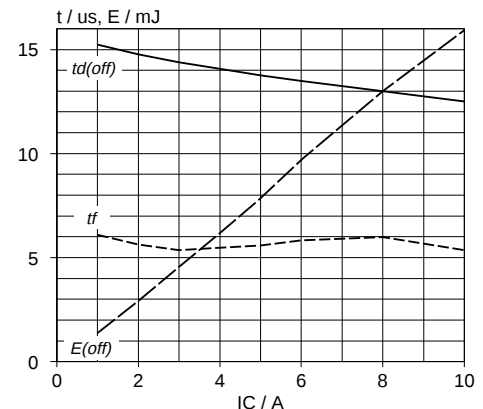


Fig.18. Typical Switching Characteristics vs. I_C
conditions: $T_J = 125^\circ\text{C}$; $V_{CL} = 300\text{ V}$; $R_G = 1\text{ k}\Omega$; $L_C = 5\text{ mH}$.

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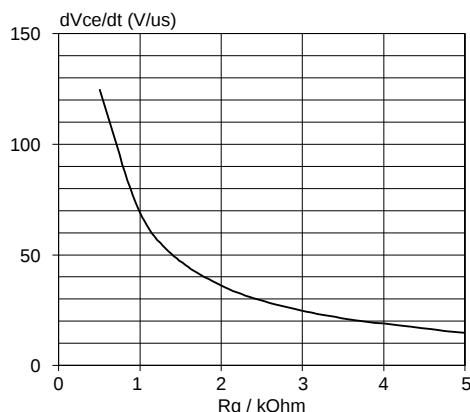


Fig.19. Typical Turn-off dV_{CE}/dt vs. R_G
conditions: $T_J=125^\circ\text{C}$; $I_C=8\text{ A}$; $V_{CL}=300\text{ V}$; $L_C=5\text{ mH}$.

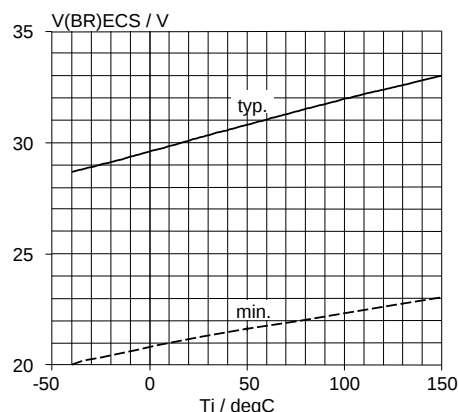


Fig.22. Reverse Breakdown Voltage
 $V_{(BR)ECS} = f(T_J)$; conditions: $I_{EC} = 50\text{ mA}$

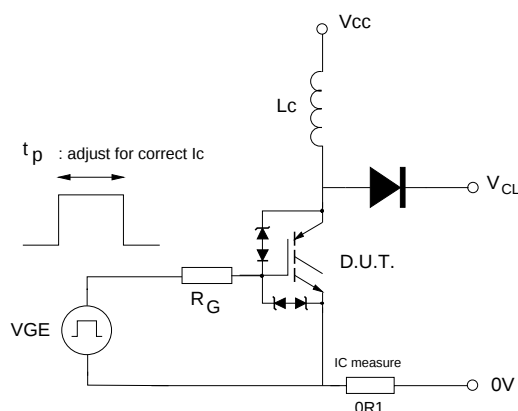


Fig.20. Test circuit for inductive load switching times.

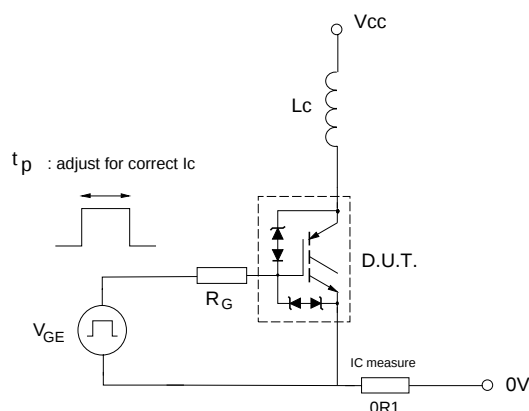


Fig.23. Test circuit for clamped turn-off energy test

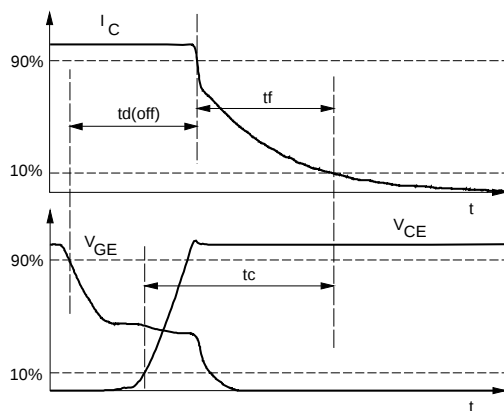


Fig.21. Definitions of inductive load switching times.

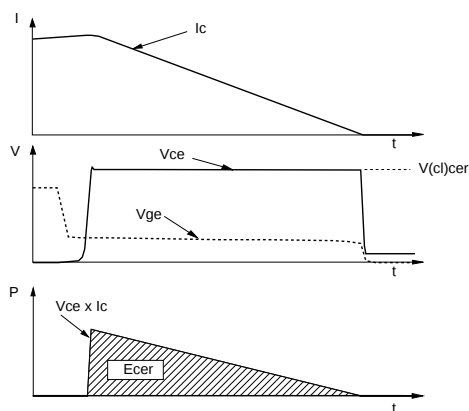
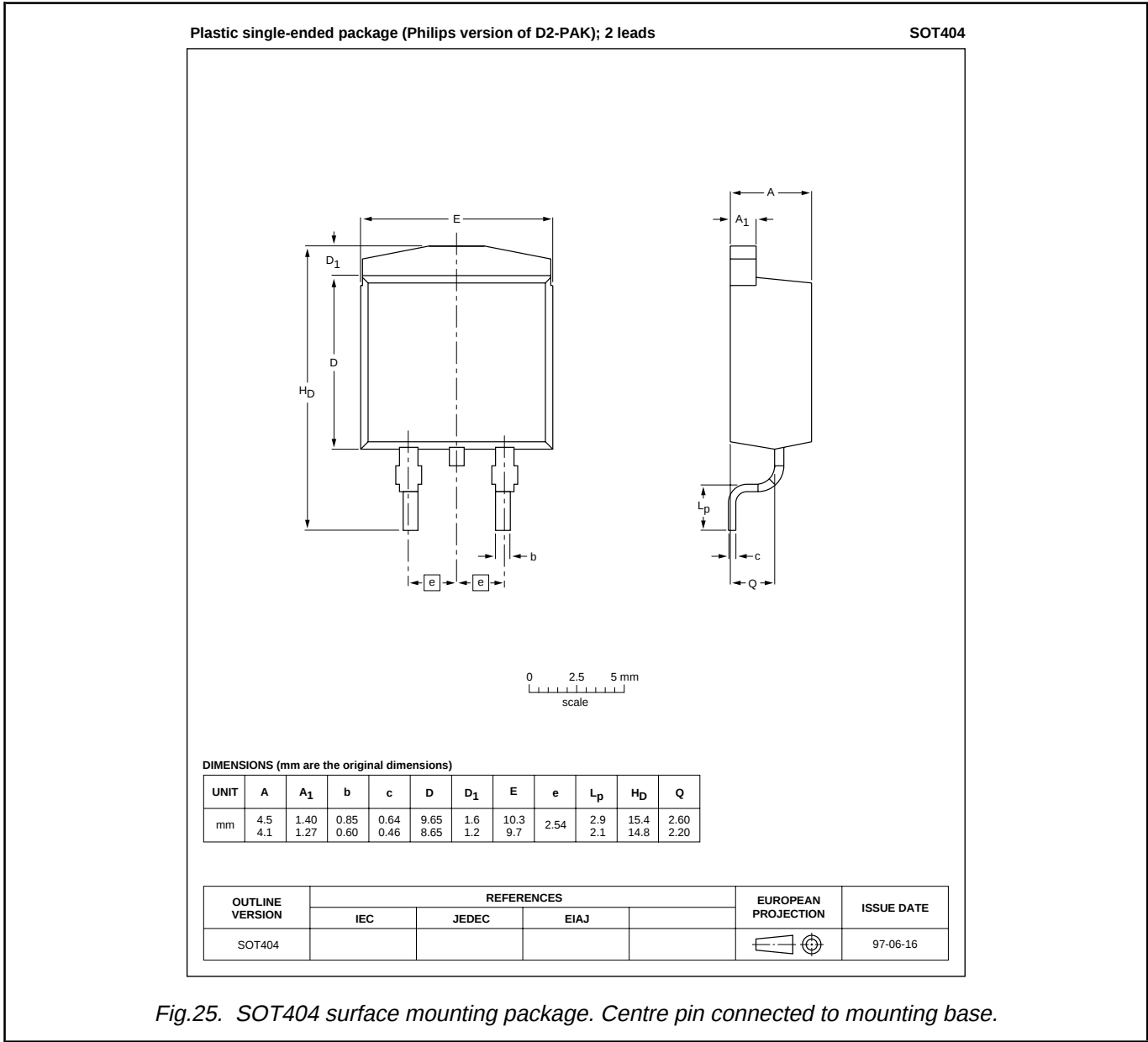


Fig.24. Definition of clamping energy E_{CER}

MECHANICAL DATA

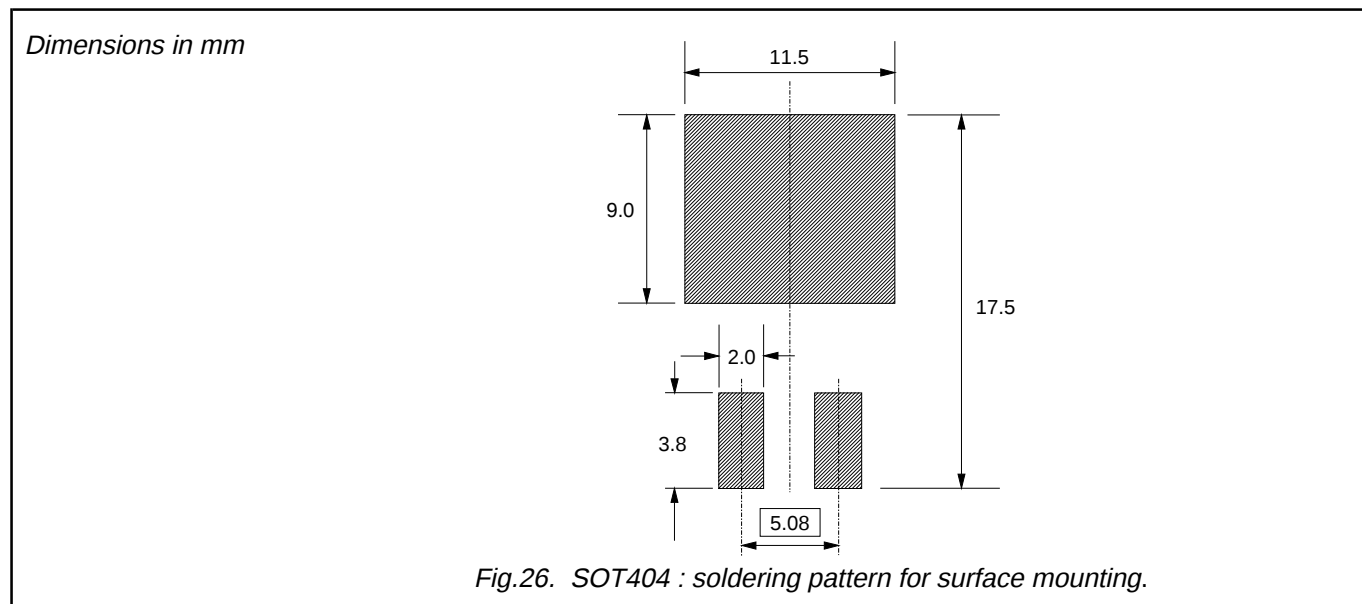


- Notes**
1. This product is supplied in anti-static packaging. The gate-source input must be protected against static discharge during transport or handling.
 2. Refer to SMD Footprint Design and Soldering Guidelines, Data Handbook SC18.
 3. Epoxy meets UL94 V0 at 1/8".

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MOUNTING INSTRUCTIONS



DEFINITIONS

Data sheet status	
Objective specification	This data sheet contains target or goal specifications for product development.
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.
Product specification	This data sheet contains final product specifications.
Limiting values	
Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.	
Application information	
Where application information is given, it is advisory and does not form part of the specification.	
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